RF Test Report

For

Applicant name:	**Jushuiliu Technologies (Shenzhen) Co., Ltd.**
Address:	Room G18415, Qianhai Apartment, Building A Factory, Yihua New Village, Zone 46, Haifu Community, Xin'an Subdistrict, Bao'an, Shenzhen
EUT name:	AI Oral Practice Device
Brand name:	Nahgnos
Model number:	CT06
Series model number:	N/A

Issued By

Company name:	**BTF Testing Lab (Shenzhen) Co., Ltd.**
Address:	Plant 101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, Guangdong, China
Report number:	BTF260819R00301
Test standards:	Article 2-1, Item 19 MIC Notice No.88 Appendix No. 43
Test conclusion:	Pass
Date of sample receipt:	2026-08-19
Test date:	2026-08-20 to 2026-08-25
Date of issue:	2026-09-01
Prepared by:	Sean.He Sean.He / Project engineer
Approved by:	Ryan.CJ / EMC Manager

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Revision History		
Version	Issue Date	Revisions Content
R_V0	2026-09-01	Original

Note:
Once the revision has been made, then previous versions reports are invalid.

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1 Introduction

1.1 Laboratory Location

Test location:	BTF Testing Lab (Shenzhen) Co., Ltd.
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Phone number:	+86-0755-23146130
Fax number:	+86-0755-23146130

1.2 Identification of the Responsible Testing Location

Test Location:	BTF Testing Lab (Shenzhen) Co., Ltd.
Address:	Plant 101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, Guangdong, China
Description:	All measurement facilities used to collect the measurement data are located at Plant 101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, Guangdong, China

1.3 Laboratory Facility

The test facility is recognized, certified, or accredited by the following organizations:

- **FCC - Designation No.: CN1409**
  BTF Testing Lab (Shenzhen) Co., Ltd. has been accredited as a testing laboratory by FCC (Federal Communications Commission). The test firm Registration No. is 695374.
- **CNAS - Registration No.: CNAS L17568**
  BTF Testing Lab (Shenzhen) Co., Ltd. is accredited to ISO/IEC 17025:2017 General Requirements for the Competence of Testing and Calibration laboratories for the competence of testing. The Registration No. is CNAS L17568.
- **A2LA - Registration No.: 6660.01**
  BTF Testing Lab (Shenzhen) Co., Ltd. is accredited in accordance with the recognized International Standard ISO/IEC 17025:2017 General requirements for the competence of testing and calibration laboratories.
- **ISED – CAB identifier.: CN0135**
  The 3m Semi-anechoic chamber of BTF Testing Lab (Shenzhen) Co., Ltd. has been Registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 27844.
- **VCCI - Registration No.: C-20122, G-20157, R-20166**
  EMC LAB: Certificated by VCCI, Japan
  Registration No.: C-20122, G-20157, R-20166
  Date of Registration: June 20, 2025
  This Certificate is valid until June 19, 2028

1.4 Announcement

(1) The test report reference to the report template version v0.
(2) The test report is invalid if not marked with the signatures of the persons responsible for preparing, reviewing and approving the test report.
(3) The test report is invalid if there is any evidence and/or falsification.
(4) This document may not be altered or revised in any way unless done so by BTF and all revisions are duly noted in the revisions section.
(5) Content of the test report, in part or in full, cannot be used for publicity and/or promotional purposes without prior written approval from the laboratory.
(6) The laboratory is only responsible for the data released by the laboratory, except for the part provided by the applicant.
(7) All entrusted information in this report is provided by the client and has been confirmed through consultation with the client; The testing items for this report have been discussed and confirmed with the client, and our company is only responsible for the content reflected in the report.

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2 Product Information

2.1 Application Information

Company name:	Jushuiliu Technologies (Shenzhen) Co., Ltd.
Address:	Room G18415, Qianhai Apartment, Building A Factory, Yihua New Village, Zone 46, Haifu Community, Xin'an Subdistrict, Bao'an, Shenzhen

2.2 Manufacturer Information

Company name:	Jushuiliu Technologies (Shenzhen) Co., Ltd.
Address:	Room G18415, Qianhai Apartment, Building A Factory, Yihua New Village, Zone 46, Haifu Community, Xin'an Subdistrict, Bao'an, Shenzhen

2.3 Factory Information

Company name:	Jushuiliu Technologies (Shenzhen) Co., Ltd.
Address:	Room G18415, Qianhai Apartment, Building A Factory, Yihua New Village, Zone 46, Haifu Community, Xin'an Subdistrict, Bao'an, Shenzhen

2.4 General Description of Equipment under Test (EUT)

EUT name:	AI Oral Practice Device
Under test model name:	CT06
Series model name:	N/A
Description of model name differentiation:	N/A
Ratings:	Input: DC 5V 1A Battery: DC 3.7V 450mAh 1.665Wh

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2.5 Technical Information

Operation Frequency:	2402-2480MHz
Channel numbers:	79
Channel separation:	1MHz
Modulation technology:	GFSK, Pi/4-DQPSK,8DPSK
The Max RF conducted output power:	0.0070mW/MHz
Antenna type:	Internal Antenna
Antenna gain:	2.50dBi

Channel List:

Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)	Channel	Frequency (MHz)
0	2402	20	2422	40	2442	60	2462
1	2403	21	2423	41	2443	61	2463
2	2404	22	2424	42	2444	62	2464
3	2405	23	2425	43	2445	63	2465
4	2406	24	2426	44	2446	64	2466
5	2407	25	2427	45	2447	65	2467
6	2408	26	2428	46	2448	66	2468
7	2409	27	2429	47	2449	67	2469
8	2410	28	2430	48	2450	68	2470
9	2411	29	2431	49	2451	69	2471
10	2412	30	2432	50	2452	70	2472
11	2413	31	2433	51	2453	71	2473
12	2414	32	2434	52	2454	72	2474
13	2415	33	2435	53	2455	73	2475
14	2416	34	2436	54	2456	74	2476
15	2417	35	2437	55	2457	75	2477
16	2418	36	2438	56	2458	76	2478
17	2419	37	2439	57	2459	77	2479
18	2420	38	2440	58	2460	78	2480
19	2421	39	2441	59	2461	/	/

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3 Summary of Test Results

3.1 Test Standards

The tests were performed according to following standards:
Article 2-1, Item 19 : 2.4GHz for SRD/BT/WIFI
MIC Notice No.88 Appendix No.43：2.4GHz band advanced low-power data communication system

3.2 Uncertainty of Test

Measurement	Value
Radio Frequency	±1.2 *10^{-9}
Occupied Channel Bandwidth	±173.1Hz
RF output power, conducted	±0.66 dB
Unwanted Emissions, Conducted	±2.32dB
Time	±5 %
The following measurement uncertainty levels have been estimated for tests performed on the EUT as specified in CISPR 16-4-2. This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of k=2.	

3.3 Summary of Test Result

Item	Standard	Requirement	Result
Tolerance of Frequency	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Occupied Bandwidth (99%)	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Spread Bandwidth (90%)	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Spread Factor	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Antenna Power and Tolerance	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Spurious Emission Intensity	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Secondary Radiated Emissions	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Dwell Time	Article 2-1, Item 19	Article 2-1, Item 19	Pass
Transmitting Antenna Absolute Gain	Article 2-1, Item 19	Article 2-1, Item 19	N/A*
Half Power Beam Angle (Radiation angle of antenna)	Article 2-1, Item 19	Article 2-1, Item 19	N/A*
Interference Prevention Function	Article 2-1, Item 19	Article 2-1, Item 19	Pass
RF Accessibility	Article 2-1, Item 19	Article 49-20, paragraph 1(a)	Pass

Remark:
1. *Pass: Meet the requirements.*
2. *N/A: not applicable.*
3. *N/A*: the E.I.R.P is less than 12.14dBm, the test item is not appliable.*

3.4 Additions to, deviations, or exclusions from the method

None

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4 Test Configuration

4.1 Test Equipment List

Spread Bandwidth (90%) Spread Factor Antenna Power and Tolerance Spurious Emission Intensity Secondary Radiated Emissions Dwell Time Tolerance of Frequency Occupied Bandwidth (99%)							
Test Equipment	Manufacturer	Model	Serial No.	Cal. Date	Cal. Due	Cal. By	Remark
Test Software	TST Pass	/	Version: 2.0	/	/	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
Cell Site Test Set	HP	8921A	US35010158	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
Spectrum Analyzer	Keysight	N9020A	MY50410020	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
ESG Vector Signal Generator	Agilent	E4438C	MY45094854	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
MXG Vector Signal Generator	Agilent	N5182A	MY46240163	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
Wideband Radio Communication Tester	Rohde&Schwarz	CMW500	161997	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
Programmable Constant Temperature And Humidity Test Chamber	ZZCKONG	ZZ-K02A	20210928007	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
DC Power Supply	Tongmen	etm-6050c	20211026123	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
RF Control Unit	Techy	TR1029-1	10291	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
RF Sensor Unit	Techy	TR1029-2	10292	2025-10-17	2026-10-16	Guangzhou LiSai Metrology &Test Co.,Ltd.	3
RF shielding box	Yinuoxin Electronics	50*50*50 cm	050505M	2025-10-21	2026-10-20	Guangzhou LiSai Metrology &Test Co.,Ltd.	3

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Remark:

1. *Calibration conducted by the National Institute of Information and Communications Technology (NICT) in. japan (hereinafter referred to as *NICT*) or a designated calibration agency under Article 102-18 paragraph (1) in JRL.*
2. *Correction conducted pursuant to the provisions of Article 135 or Article 144 of the Measurement Act (Act. No.51 of 1992)*
3. *Calibration conducted in countries except Japan, which shall be equivalent to the calibration conducted by. the NICT or a designated calibration agency under Article 102-18 paragraph (1).*
4. *Calibration, etc. conducted by using measuning instruments and other equipment listed in the right column of appended table No. 3, which shall have been given any type of calibration, etc. listed above from (2) to (4).*
   From JRL Article 24-2, paragraph 4, Item 2

All calibration information is from Guangzhou LiSai Metrology &Test Co., Ltd.

4.2 Test Auxiliary Equipment

The EUT has been tested as an independent unit.

4.3 Environment Condition

ENV	Temperature (°C)	Voltage (VDC)
NTNV	15~35	3.70
NTHV	15~35	4.07
NTLV	15~35	3.33

Voltage fluctuation test:

The RF unit is supplied DC 3.3V The fluctuation of input voltage to the circuit of RF unit of test equipment is under ±1%, when input voltage DC 5.0V fluctuated ±10%, so all measurement has been conducted by only rated voltage.

DC Input	RF_IC Input	Rate of fluctuation(%)
3.70V	3.3V	0.0
4.07V	3.3V	0.0
3.33V	3.3V	0.0

4.4 Test Modes

No.	Test Modes
TM1	TX mode
TM2	RX mode

4.5 Test Channel of EUT

Operation Band: 1

Bandwidth (MHz)	Lowest Channel (LCH) (MHz)	Middle Channel (MCH) (MHz)	Highest Channel (HCH) (MHz)
1	2402	2441	2480

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5 Evaluation Results (Evaluation)

5.1 Interference Prevention Function

Test Requirement:	The EUT shall support one of the following functions: - Automatic identification transmission - Automatic identification reception
Test Method:	Notification No.88 of MIC, 2004
Procedure:	(1) For EUTs capable of automatically transmitting identification data a. Transmit identification data from EUT to Demodulator b. Confirm identification data is correctly received by Demodulator (2) For EUTs capable of automatically receiving identification data a. Transmit identification data from Link Partner to EUT b. Confirm communication link is established c. Link Partner shall respond by transmitting different identification data back to the EUT d. Confirm EUT stops transmitting, or confirm EUT recognizes that the two identification data are different
Operating Environment:	
Temperature:	25.8 °C
Humidity:	47.1 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

5.1.1 Conclusion

The detected ID of the device is below:
D0:F1:B9:81:23:40
Test result: The device meet the requirements
PASS

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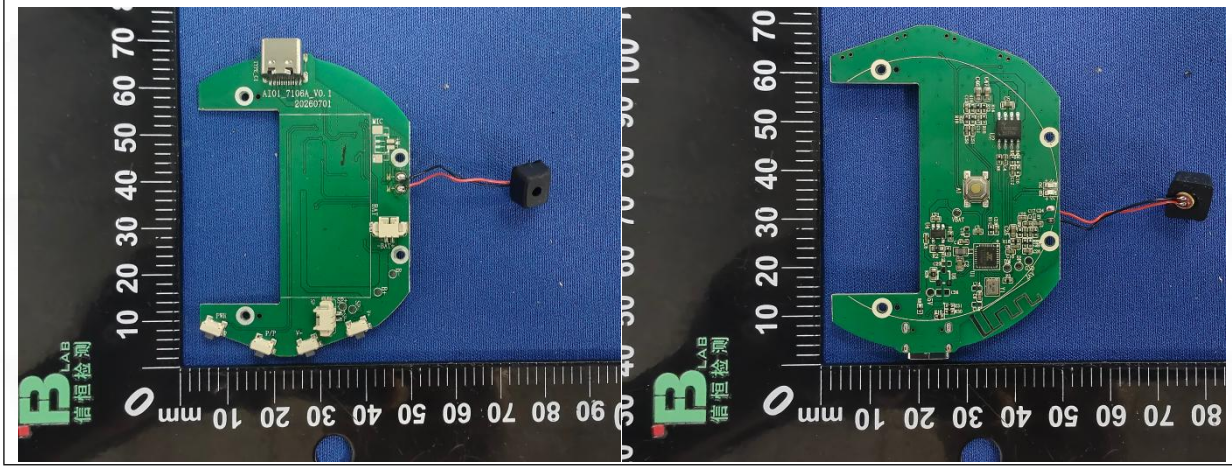
5.2 RF Accessibility

Test Requirement:	The EUT shall be constructed in such a way that sensitive RF parts, (like modulation and oscillator parts) cannot be reached easily by the user. These parts shall be covered by soldered metal caps or glue or by other mechanical covers. If the covers are fixed with screws, these shall be not the common type(s) like a Phillips, but special versions like Torx, so that the user cannot open the device with common tools.
Operating Environment:	
Temperature:	23.9 °C
Humidity:	52.3 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

5.2.1 Conclusion

Tamper proof declaration:
□ RF and Modulation parts are mounted on PCB with surface mount technology, and there is no any adjustable parts on PCB or adjustable parts are not exposed.



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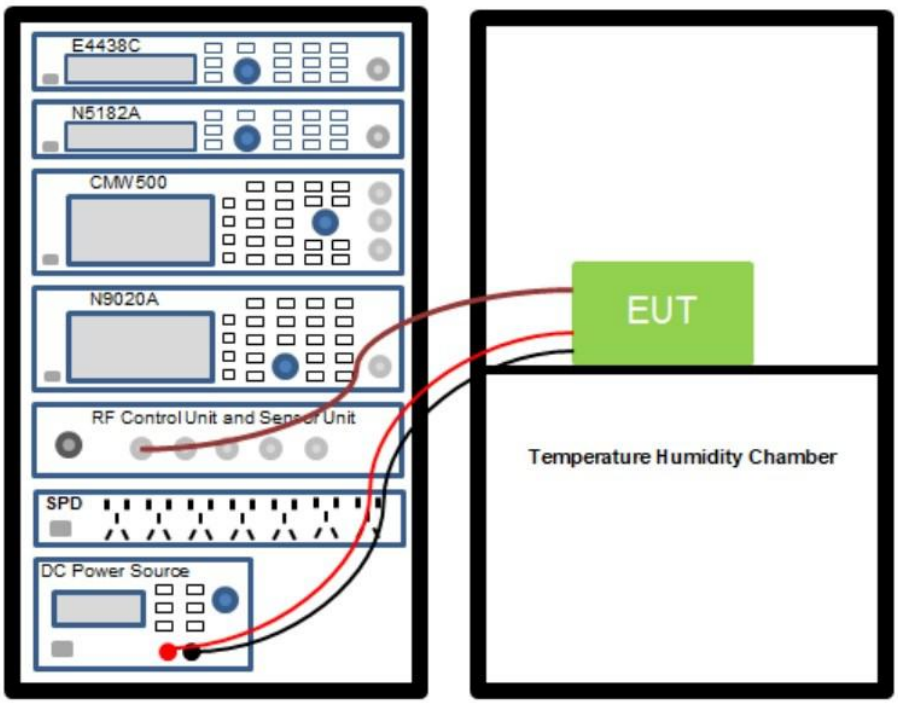
6 Radio Spectrum Matter Test Results (RF)

6.1 Tolerance of Frequency

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	±50ppm or less.
Procedure:	Center frequency: Test frequency Span: 2 times channel bandwidth RBW: 100 kHz (Modulation ON) VBW: 100 kHz (Modulation ON) Sweep data points: 1001 or greater Sweep time: Auto Detector mode: Positive peak Indication mode: Max hold If the EUT cannot transmit in un-modulated mode then modulated mode measurements can be made, as follows: If the spectrum observed using the spectrum analyzer has a characteristic dip at the center, then the center frequency of the dip shall be regarded as the center frequency of the carrier.
Test Setup:	
Operating Environment:	
Temperature:	25 °C
Humidity:	48.2 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.1.1 Test Data

Please Refer to Appendix for Details.

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6.2 Occupied Bandwidth (99%)

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	For FHSS or FHSS and other modulation Hybird: 83.5 MHz or less: The measured bandwidth at the low and high channels shall meet the following requirements: - The lowest frequency of the measured bandwidth shall not be less than 2400 MHz - The highest frequency of the measured bandwidth shall not be greater than 2483.5 MHz [Occupied Bandwidth] 83.5 MHz or less
Procedure:	

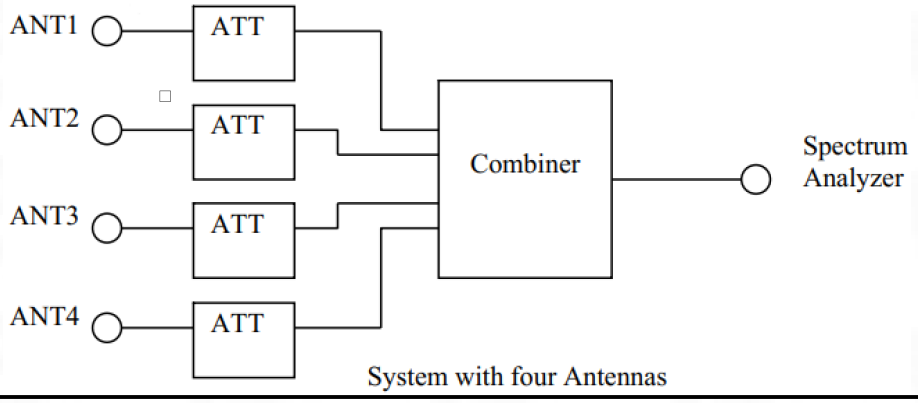
Center Frequency:	Test frequency
Span:	2 - 3.5 times the technical standard
RBW:	Within 3% of the technical standard
VBW:	Same as RBW
Sweep time:	Auto
Sweep data points:	1001 or greater
Detector mode:	Positive peak
Indication mode:	Max hold
BW setting:	99%

(1) Measure the signal bandwidth using a spectrum analyzer

(2) For multiple antenna systems:

a) Each antenna shall be individually measured

b) If the measured occupied bandwidth for any antenna exceeds [(Occupied Bandwidth Limit) – 100kHz] then, in addition, the occupied bandwidth shall be measured with all antennas combined – see diagram below:



System with four Antennas

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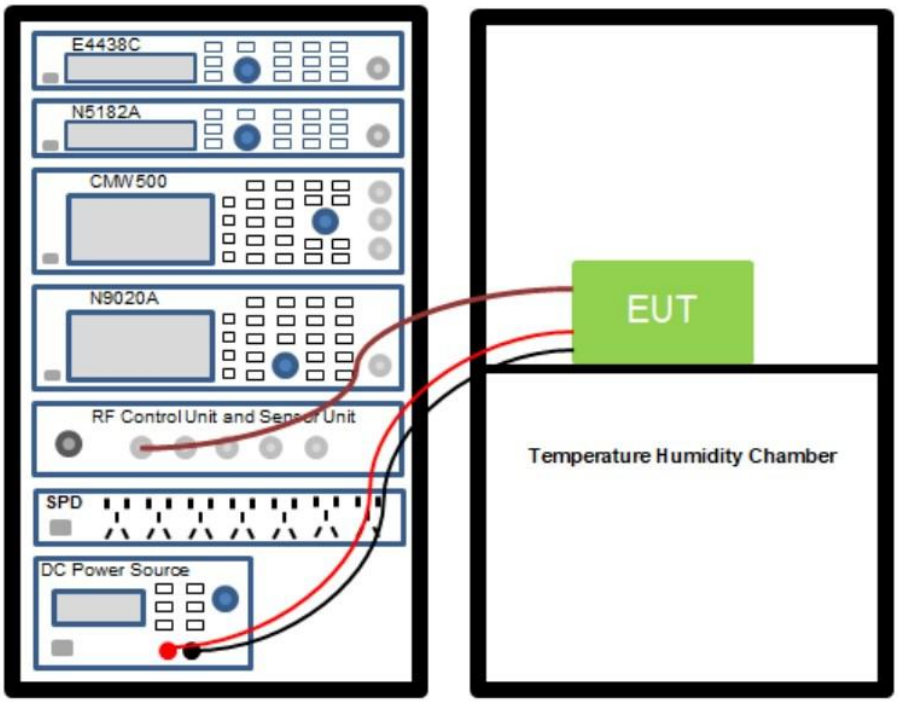
Test Setup:	
Operating Environment:	
Temperature:	22.8 °C
Humidity:	50.1 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.2.1 Test Data

Please Refer to Appendix for Details.

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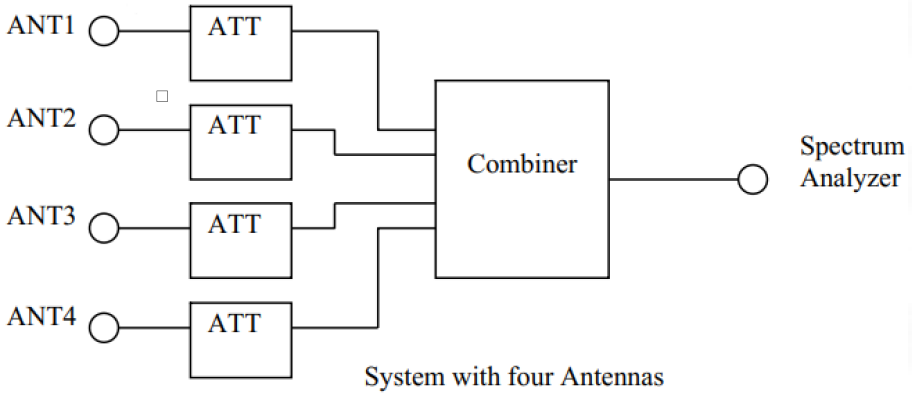
6.3 Spread Bandwidth (90%)

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	Only for report use.
Procedure:	

Center Frequency:	Test frequency
Span:	2 - 3.5 times the technical standard
RBW:	Within 3% of the technical standard
VBW:	Same as RBW
Sweep time:	Auto
Sweep data points:	1001 or greater
Detector mode:	Positive peak
Indication mode:	Max hold
BW setting:	90%

(1) Measure the signal bandwidth using a spectrum analyzer
(2) For multiple antenna systems:
a) Each antenna shall be individually measured
b) If the measured occupied bandwidth for any antenna exceeds [(Occupied Bandwidth Limit) – 100kHz] then, in addition, the occupied bandwidth shall be measured with all antennas combined – see diagram below:



System with four Antennas

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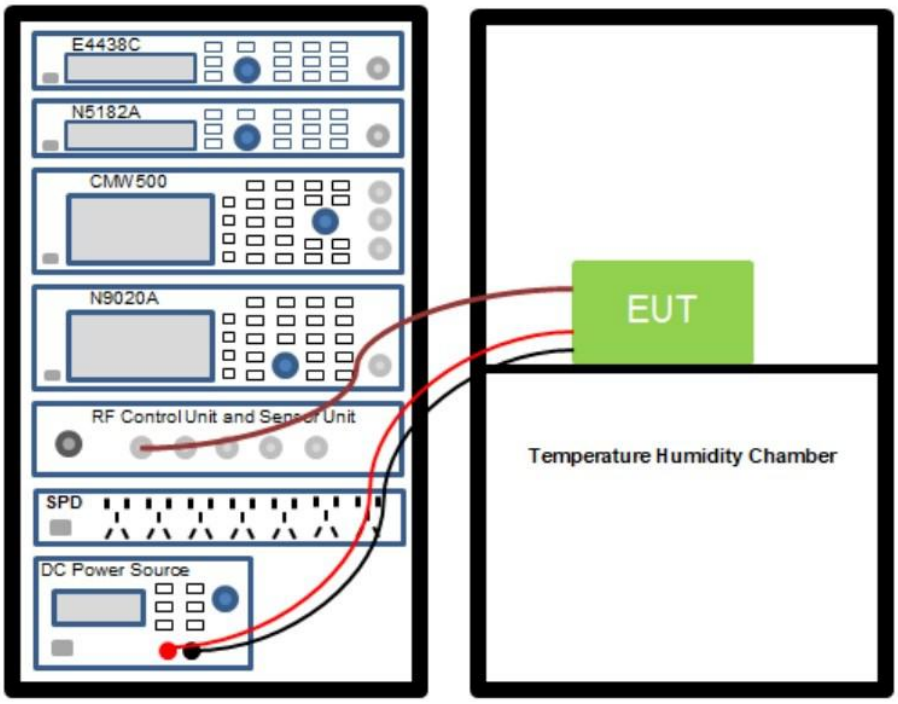
Test Setup:	
Operating Environment:	
Temperature:	25.9 °C
Humidity:	49.1 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.3.1 Test Data

Please Refer to Appendix for Details.

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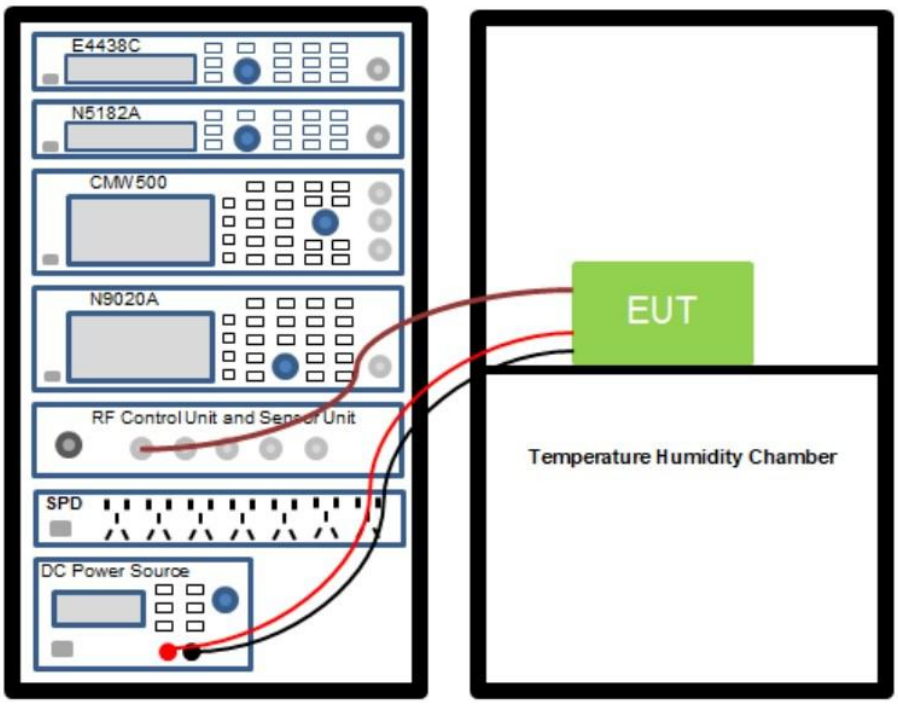
Plant 101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, Guangdong, China
Email: info@btf-lab.com Tel: +86-0755-23146130 http://www.btf-lab.com

6.4 Antenna Power and Tolerance

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	Antenna Power: 3 mW/MHz or less Tolerance: +20% or less EIRP: 16.91dBm/MHz
Procedure:	1. Measure the total power by the Power Meter in a state of hopping mode. 2.Calculate the mean power per 1MHz by dividing the reading level by spread bandwidth. Output power Density (mW/MHz) = Total power (mW) / spread bandwidth(MHz)
Test Setup:	
Operating Environment:	
Temperature:	23.9 °C
Humidity:	46.6 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.4.1 Test Data

Please Refer to Appendix for Details.

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6.5 Spurious Emission Intensity

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	(1) Below 2387 MHz: 2.5 μW (-26 dBm)/MHz or less (2) 2387 to 2400 MHz: 25.0 μW (-16 dBm)/MHz or less (3) 2483.5 to 2496.5 MHz: 25.0 μW (-16 dBm)/MHz or less (4) Over 2496.5 MHz: 2.5 μW (-26 dBm)/MHz or less
Procedure:	[Setting 1] Frequency range: (see Note 1) RBW: 1 MHz VBW: 1 MHz Sweep time: Minimum time required to make an accurate measurement Sweep Data Points: 1001 or greater Detector mode: Positive peak Indication mode: Max hold (see Note 2) Note 1: Measurement range shall be 30 MHz to 12.5 GHz, except for the following cases: -FHSS, FHSS+DSSS, FHSS+OFDM:2374 MHz to 2509.5 MHz -Other than FHSS, FHSS+DSSS, FHSS+OFDM: 2400 MHz to 2483.5 MHz Note 2: Sweep shall be repeated until the max hold waveform is stable. [Setting 2] Center frequency: Frequency of spurious emission found using [Setting 1] Span: 0 Hz RBW: 1 MHz VBW: 1 MHz Sweep time: Minimum time required to make an accurate measurement. For burst type (intermittent) spurious emissions, sweep time shall be greater than one burst interval Sweep Data Points: 1001 or greater Detector mode: Sample [Setting 3] Frequency range: 2374 MHz to 2400 MHz 2483.5 MHz to 2509.5 MHz RBW: 30 kHz VBW: 30 kHz Sweep time: Minimum time required to make an accurate measurement. Sweep data points: 1001 or greater Detector mode: Positive peak Indication mode: Max hold (1) After configuring the spectrum analyzer to [Setting 1], search for spurious emissions from 30 MHz to 12.5 GHz. If the sweep range does not cover the required measurement frequency range then the measurement range will need to

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be divided into sufficient sections of size [RBW x Sweep Data Points]. If spurious emissions greater than [Limit - 3dB] are found, then more detailed measurements are required, go to step (2)
(2) Configure the spectrum analyzer using [Setting 2] and measure the average signal amplitude.
If the spurious emission is burst type (intermittent), then the average value shall not include signal OFF time.
If spurious emissions ranging from 30 MHz to 2374 MHz and from 2509.5MHz to 12.5GHz are over the limit, then the test result is Fail.
If spurious emissions ranging from 2374 MHz to 2400 MHz and from 2483.5 MHz to 2509.5 MHz are over the limit, then further detailed measurements are required, go to step (3)
(3) In the following cases, measure the spurious emissions using [Setting 3]
- Case1: FHSS, FHSS+DSSS, FHSS+OFDM
- Case2: Other than FHSS, FHSS+DSSS, FHSS+OFDM, and the spurious emissions in step (2) are over the limit
(4) Calculate the spurious emission value (Calculated Value) using following the formula below:
Calculated Value = (Measured Value using (3) + 15.2dB)
Note: 15.2dB adjustment is derived from the Conversion Factor of RBW
Conversion Factor of RBW = 10 x Log (Reference Bandwidth / RBW of measurement) = 15.2 [dB] Where: Reference Bandwidth = 1 MHz
RBW of measurement = 30 kHz
(5) If the calculated value using (4) is over the Limit (section 6.7), go to (6)
(6) Configure the spectrum analyzer to [Setting 3] then make the following changes:
Frequency: Frequency of spurious emission
Span: 1 MHz
(7) After sweep, send the span data set to the PC
(8) Convert measured data from dBm to Watts
(9) Sum all the data using the formula below. If the sum is within the limit, the test result is Pass, otherwise, Fail

$$P_s = (\sum_{i=1}^{n} E_i) \times \frac{S_w}{RBW \times k \times n}$$

Ps: Sum (Watts)
Ei: Measured value at each point in the Span (Watts) Sw: Span (1MHz)
n: Number of measurement points in the Span
k: Correction factor for Equivalent Noise Bandwidth, specific to each spectrum analyzer, check the instrument user guide
RBW: Resolution Bandwidth (MHz).
(10) If the EUT has multiple antennas, measure the spurious emission form each individual antenna using steps (1) through (9)
(11) Convert the individual antenna spurious level measurements (step (10)) from dB to absolute values
(12) Combine (sum) the absolute values of the spurious measurements at each frequency for each antenna (to create a single composite spectrum of spurious emissions)
(13) Ensure that the composite spectrum does not exceed the Limit defined in 6.7 (Technical Standard)
(14) Configuring the spectrum analyzer using [Setting 3] and measure the spurious emissions with all the antennas electrically combined

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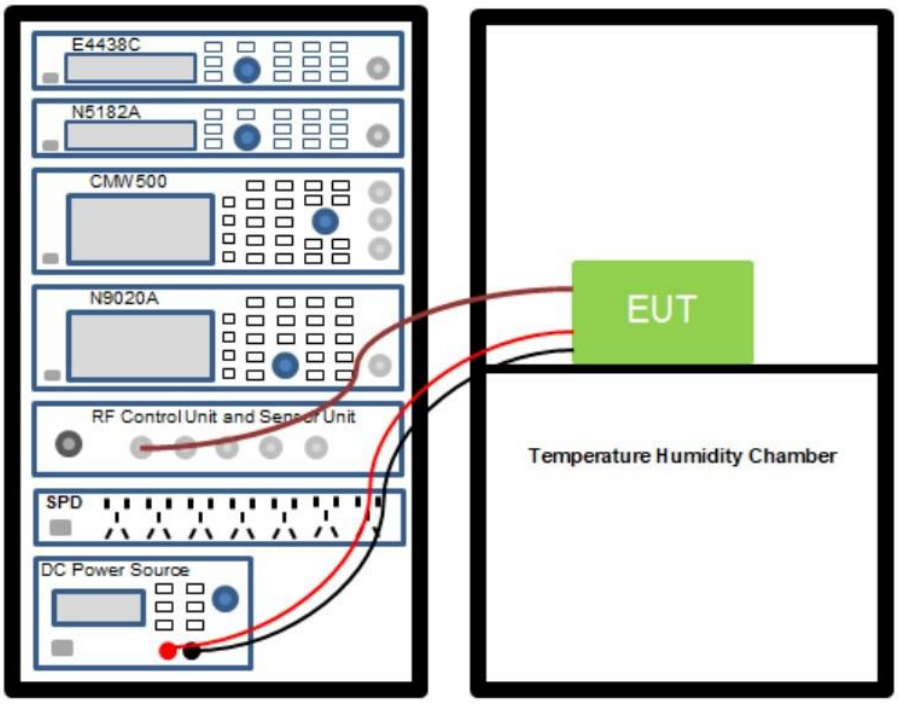
Test Setup:	
Operating Environment:	
Temperature:	24.4 °C
Humidity:	46.2 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.5.1 Test Data

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6.6 Secondary Radiated Emissions

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	(1) Below 1 GHz: 4 nW (-54dBm) or less (2) Above 1 GHz: 20 nW (-47dBm) or less
Procedure:	[Setting 1] Frequency range: 30 MHz ~ 12.5 GHz RBW: Below 1 GHz:100 kHz Above 1 GHz:1 MHz VBW: Below 1 GHz:100 kHz Above 1 GHz:1 MHz Sweep time: Auto Sweep data points: 1001 or greater Detector mode: Positive peak Indication mode: Max hold [Setting 2] Center Frequency: Frequency of spurious emission found using [Setting 1] Span: 0 Hz RBW: Below 1 GHz:100 kHz Above 1 GHz:1 MHz VBW: Below 1 GHz:100 kHz Above 1 GHz:1 MHz Sweep time: Auto Sweep data points: 1001 or greater Detector mode: Sample (1) Configure the spectrum analyzer to [Setting 1] and then search for spurious emissions in the range 30 MHz to 12.5GHz. If the sweep range does not cover the required measurement frequency range then the measurement range will need to be divided into sufficient sections of size [RBW x Sweep Data Points]. (2) If spurious emissions are found with an amplitude greater than [Limit - 10dB] then perform further detailed measurements as described in (3) (3) Configure the spectrum analyzer using [Setting 2] and measure the average signal amplitude. If the spurious emission is burst type (intermittent), then the average value shall not include signal OFF time Multiple Antenna Systems If the EUT has multiple antennas then emissions from each antenna shall be measured individually, as described below (4) For each antenna repeat steps (1) through (3). Convert all spurious level measurements from dB to absolute value (5) Combine (sum) the absolute values of the spurious measurements at each frequency for each antenna (to create a single composite spectrum of spurious emissions) (6) Ensure that the composite spectrum does not exceed the Limit

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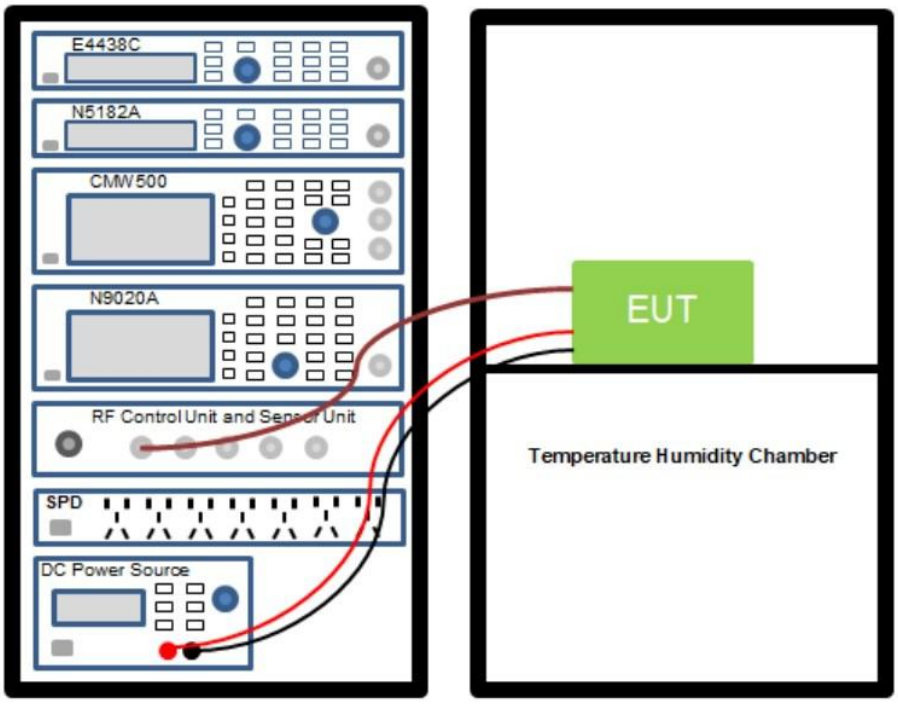
Test Setup:	
Operating Environment:	
Temperature:	22.4 °C
Humidity:	50.6 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.6.1 Test Data

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Plant 101, 201 and 301, Building 1, Block 2, Tantou Industrial Park, Tantou Community, Songgang Street, Bao'an District, Shenzhen, Guangdong, China
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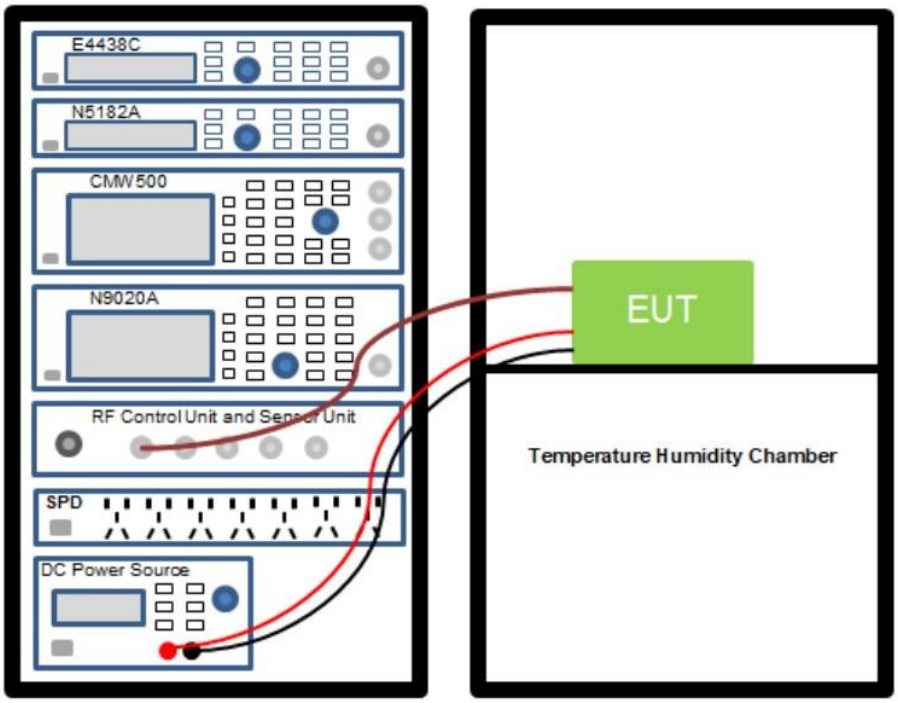
6.7 Dwell Time

Test Requirement:	Article 2-1, Item 19
Test Method:	Notification No.88 of MIC, 2004
Test Limit:	Transmit ON Time shall be less than 0.4 seconds Total Dwell Time shall be less than 0.4 seconds
Procedure:	[Setting 1] Frequency: Test frequency Span: 0 Hz RBW: 1 MHz VBW: 1 MHz Sweep data points: 1001 or greater Trigger: Video trigger Detection mode: Positive peak (1) Configure the spectrum analyzer to [Setting 1] (2) Measure the Burst Cycle and Transmit ON Time (3) Total Dwell Time shall be calculated by the following formula: Total Dwell Time = (0.4 x Spreading Rate x Transmit ON Time) / (Burst Cycle x Number of Hopping Channels) [Notes] a. Spreading Rate = Spread Bandwidth (measured value) / Transmission Rate b. Transmit ON Time and Burst Cycle are both measured in Seconds c. Numerical Coefficient (0.4) is a dimensionless number defined in the technical standard
Test Setup:	
Operating Environment:	
Temperature:	24.8 °C
Humidity:	49.1 %
Atmospheric Pressure:	1010 mbar
Test voltage:	DC 3.70V

6.7.1 Test Data

Please Refer to Appendix for Details.

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7 Test Setup Photos

Please refer to Appendix I Test Setup Photos.

8 EUT Constructional Details (EUT Photos)

Please refer to Appendix II External Photos and Appendix III Internal Photos.

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